

25-45GHz Driver

GaAs Monolithic Microwave IC in bare die

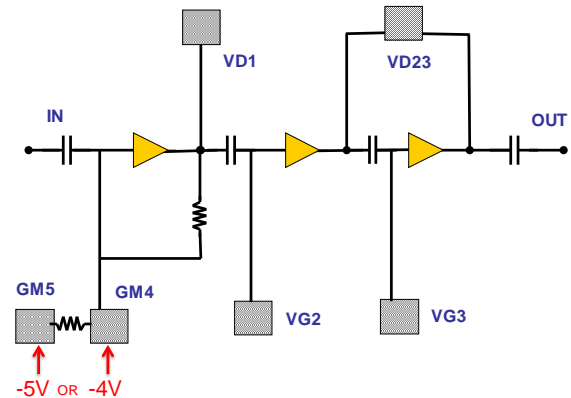
Description

The CHA3409-98F is a 3 stage monolithic Medium Power Amplifier, which produces 23dB linear gain and 19dBm output power. It includes a self-biasing on the first stage, which reduces the impact of temperature and technology variations.

It is well suited for a wide range of application from military to commercial communication systems and test instrumentation.

This product is manufactured with a pHEMT process, 0.15 μ m gate length, via holes through the substrate, air bridges and electron beam gate lithography.

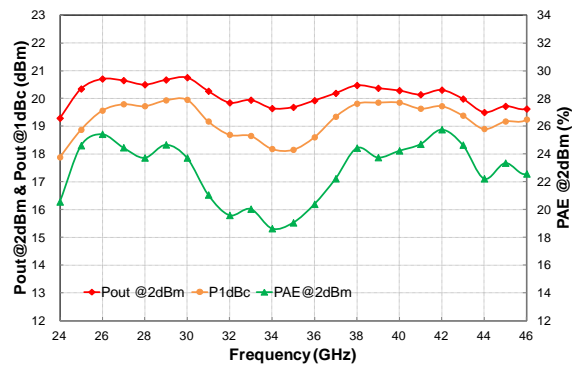
It is available in bare die with BCB protection layer.



Main Features

- Broadband performances: 25-45GHz
- 19dBm Pout at 1dB compression
- 23dB linear gain
- 19% of PAE @ 1dBc
- DC bias: Vd=4Volt @ Id=100mA
- Chip size 2x1.3x0.1 (mm)

Output power & PAE vs frequency



Main Electrical Characteristics

Tamb = +25°C, Vg_{stg1}=-4V, Vd=4V, Idq=100mA

| Symbol | Parameter | Min | Typ | Max | Unit |
|--------|-------------------------|-----|-----|-----|------|
| Freq | Frequency range | 25 | | 45 | GHz |
| Gain | Linear Gain | | 23 | | dB |
| P-1dB | Output Power @1dB comp. | | 19 | | dBm |
| Psat | Saturated output power | | 20 | | dBm |
| PAE | PAE @1dB comp. | | 19 | | % |

Specifications (CW mode)

Tamb=+25°C, Vd=+4.0V

| Symbol | Parameter | Min | Typ | Max | Unit |
|--------------------|---|-----|------------|-----|-------|
| Fop | Operating frequency range | 25 | | 45 | GHz |
| Gain | Linear Gain | | 23 | | dB |
| ΔG | Gain variation in temperature | | ± 0.03 | | dB/°C |
| P _{-1dB} | Output power @ 1dB gain compression | | 19 | | dBm |
| Psat | Saturated Output Power | | 20 | | dBm |
| PAE | PAE at saturation | | 19 | | % |
| NF | Noise figure | | 6.5 | | dB |
| RLin | Input Return Loss | | -10 | | dB |
| RLout | Output Return Loss | | -11 | | dB |
| Idq | Quiescent Drain current | | 100 | | mA |
| Vg | Gate voltage of 2 nd & 3 rd stage | | -0.4 | | V |
| Vg _{stg1} | Gate voltage of the 1 st stage | | -4 | | V |

These values are representative of measurement in test fixture with a bonding wire of typically 0.25nH to 0.3nH.

Typical Bias Conditions

Tamb = +25°C

| Symbol | Parameter | Values | Unit |
|-------------------|--|--------|------|
| GM4 | GM4 OR GM5 | -4 | V |
| GM5 | DC Gate voltage : 1 st stage | -5 | V |
| G2 ⁽¹⁾ | DC Gate voltage : 2 nd stage | -0.4 | V |
| G3 ⁽¹⁾ | DC Gate voltage : 3 rd stage | -0.4 | V |
| D1 | DC Drain voltage : 1 st stage | 4 | V |
| D23 | DC Drain voltage : 2 nd & 3 rd stage | 4 | V |

⁽¹⁾Corresponding to Idq=100mA

Biasing procedure

Device Power Up instructions:

1. Ground the device
2. Bias PA gate voltage at Vgs close to Vpinch-off (example: 1st stage Vgs \approx -7V and 2nd & 3rd stage Vgs \approx -1.5V)
3. Apply Vds quiescent bias voltage (Example: Vd = 4V)
4. Increase slowly 1st stage Vgs (GM4) up to -4V and 2nd & 3rd stage Vgs up to quiescent bias drain current Idq (100mA for total Idq current)
5. Apply RF input power

Device Power Down instructions:

1. Remove RF input power
2. Decrease MPA gate voltage down to Vgs -1.5V for the 2nd & 3rd stage Vgs and -7V for the first one
3. Decrease drain voltage down to 0V

Absolute Maximum Ratings ⁽¹⁾

Tamb = +25°C

| Symbol | Parameter | Values | Unit |
|--------|--|-----------|------|
| Vd | Drain bias voltage | 8 | V |
| Idq | Drain bias current | 200 | mA |
| Vg | Gate bias voltage of 2 nd & 3 rd stage | -2.5 to 0 | V |
| Pin | Maximum peak input power overdrive | 10 | dBm |
| Tj | Junction temperature under ROR conditions | 175 | °C |

⁽¹⁾ Operation of this device above anyone of these parameters may cause permanent damage.

Recommended Operating Range ⁽³⁾ ⁽⁴⁾

Tamb = +25°C

| Symbol | Parameter | Values | Unit |
|--------------------|--|-----------|------|
| Vd | Drain bias voltage | 3 to 5 | V |
| Idq | Drain bias current | 100 | mA |
| Vg | Gate bias voltage of 2 nd & 3 rd stage | -2.5 to 0 | V |
| Vg _{stg1} | Gate voltage of the 1 st stage (GM4 or GM5) | -4 or -5 | V |
| Pin | Maximum peak input power overdrive | 10 | dBm |

⁽³⁾ Electrical performances are defined for specified test conditions

⁽⁴⁾ Electrical performances are not guaranteed over all recommended operating conditions

Temperature Range

| | | | |
|------|-----------------------------|-------------|----|
| Tamb | Operating temperature range | -40 to +85 | °C |
| Tstg | Storage temperature range | -55 to +150 | °C |

Device thermal information

The device thermal performances below are based on UMS rules to evaluate the junction temperature.

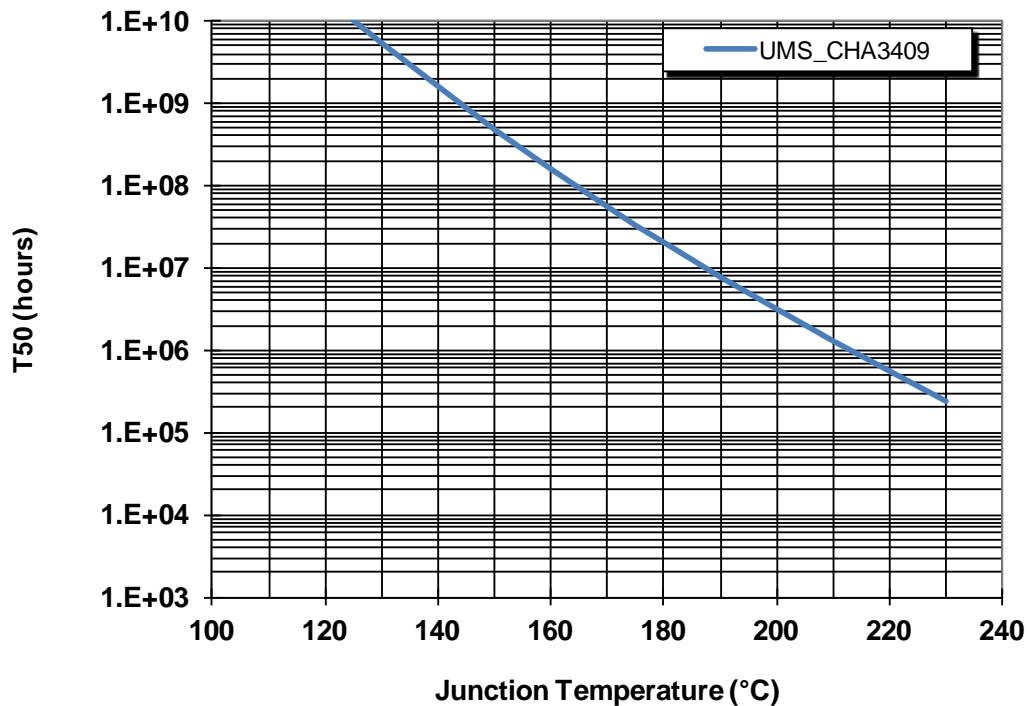
The temperature $T_{b_{chip}}$ is defined as the chip back side. The thermal resistance (R_{th_eq}) is given for the full circuit, and assumes CW operation mode in the table.

| | | | | |
|-----------------------------------|--------------|--|-----|-----------------------------|
| Thermal Resistance ⁽¹⁾ | R_{th_eq} | $T_{b_{chip}} = 85^{\circ}\text{C}$, $V_d = 4\text{V}$, $V_{g_{stg1}} = -4\text{V}$, $I_{dq} = 100\text{mA}$ | 116 | $^{\circ}\text{C}/\text{W}$ |
| Junction Temperature | T_j | $P_{in} = -10\text{dBm}$, $P_{out} = 11\text{dBm}$, $P_{diss} = 390\text{mW}$ | 160 | $^{\circ}\text{C}$ |

⁽¹⁾ Thermal resistance given from junction to back side of the chip

| | | | | |
|-----------------------------------|--------------|--|-----|-----------------------------|
| Thermal Resistance ⁽¹⁾ | R_{th_eq} | $T_{b_{chip}} = 85^{\circ}\text{C}$, $V_d = 4\text{V}$, $V_{g_{stg1}} = -4\text{V}$, $I_{dq} = 100\text{mA}$ | 116 | $^{\circ}\text{C}/\text{W}$ |
| Junction Temperature | T_j | $P_{in} = 2\text{dBm}$, $P_{out} = 20\text{dBm}$, $P_{diss} = 355\text{mW}$ | 154 | $^{\circ}\text{C}$ |

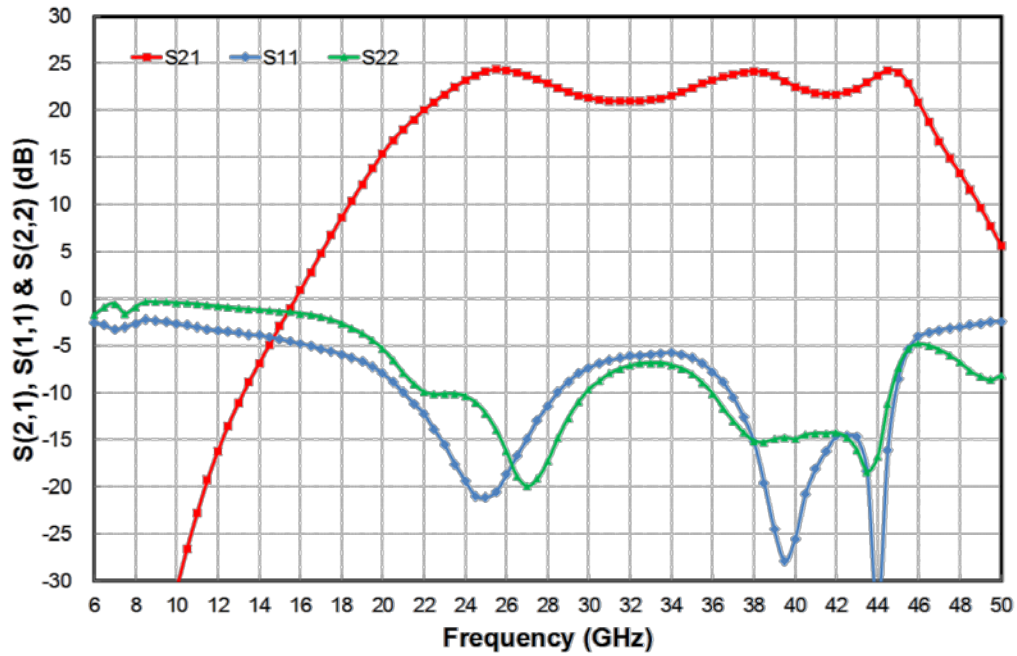
⁽¹⁾ Thermal resistance given from junction to back side of the chip. Thermal analysis is highly recommended, more details are available on request.



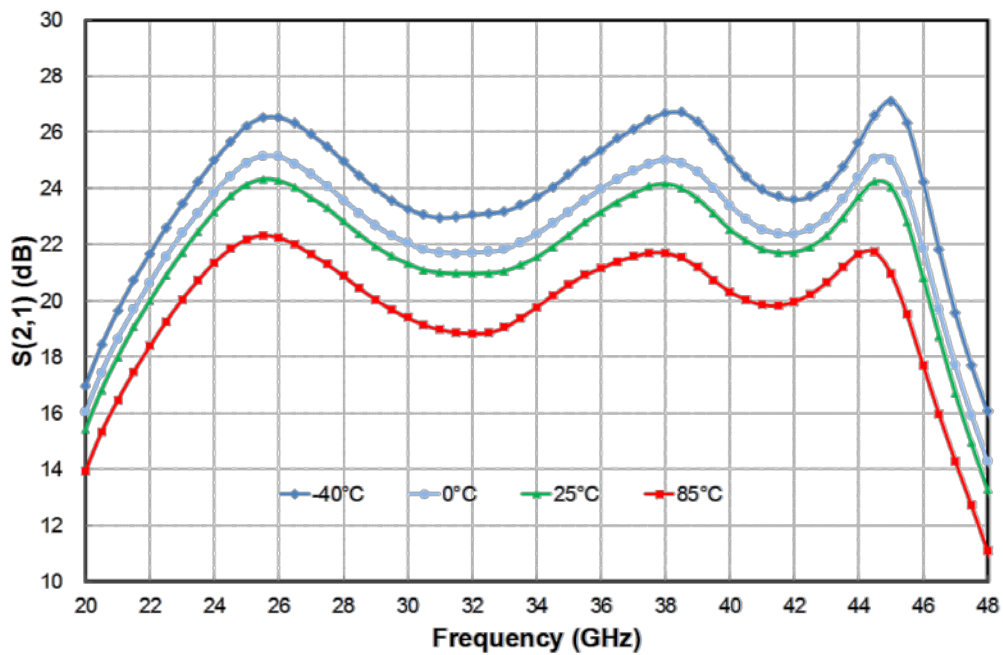
Typical On Board Sij Measurements

Tamb = +25°C, Vd = +4V, Vg1=-4V, other Vg fixed for Idq = 100mA@25°C
 Measurement performed on test board in the bonding wire access plans on the PCB.

Small Signal Gain (dB) and Input and Output Return Losses (dB) @25°C



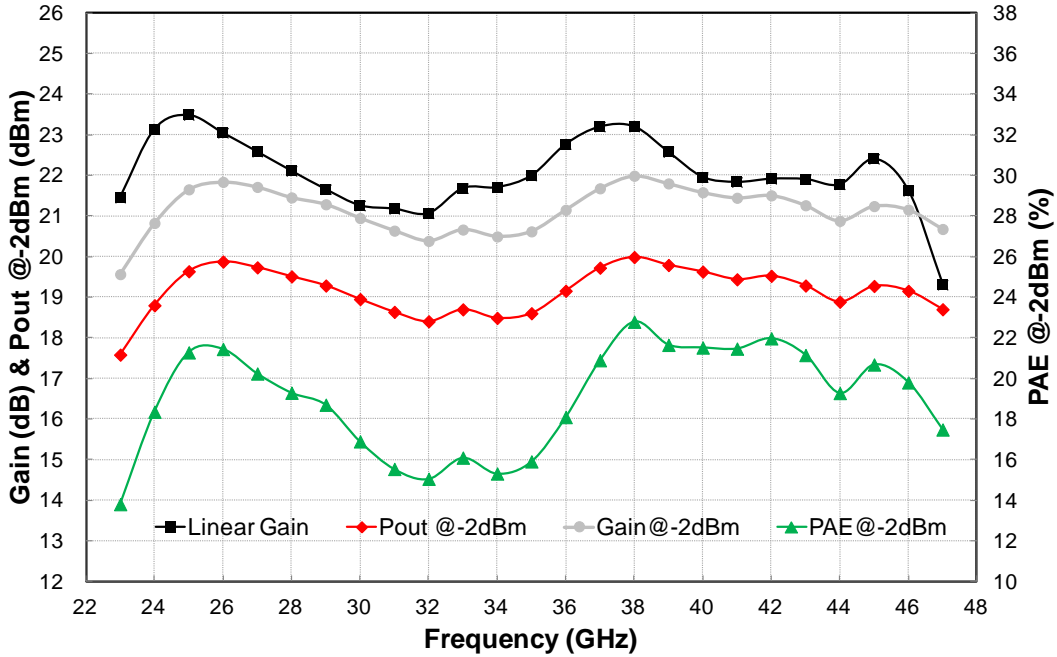
Small Signal Gain (dB) versus Frequency (GHz) and temperature (°C)



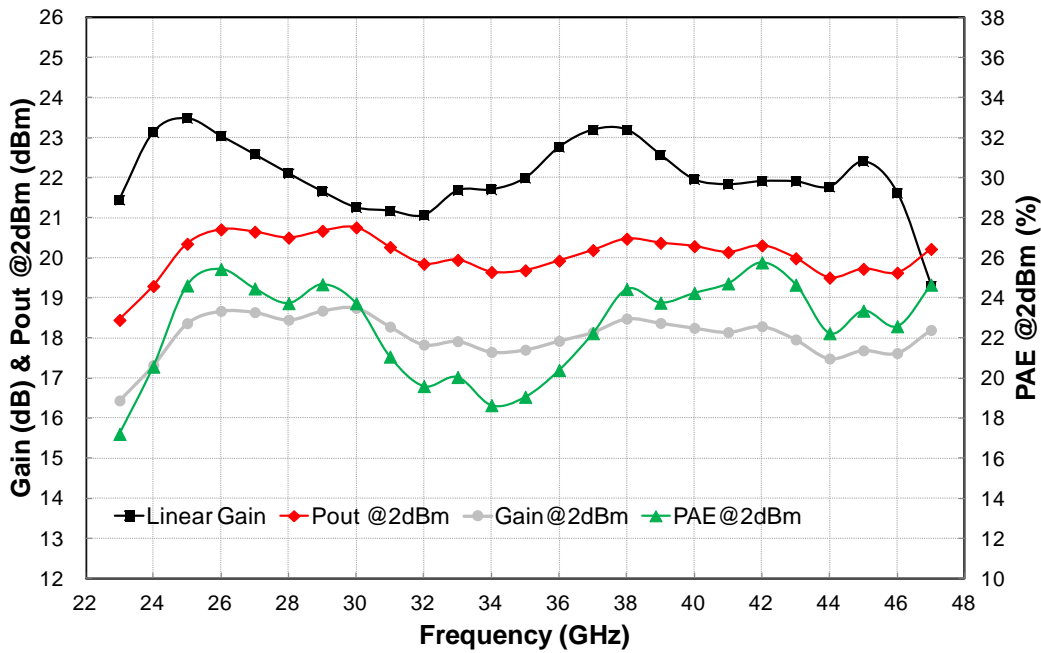
Typical On Board Measurements (CW)

Tamb = +25°C, Vd = +4V, Vg1=-4V, other Vg fixed for Idq = 100mA@25°C
 Measurement performed on test board in the bonding wire access plans on the PCB.

Linear Gain & Gain, Pout & PAE versus Frequency @Pin=-2dBm



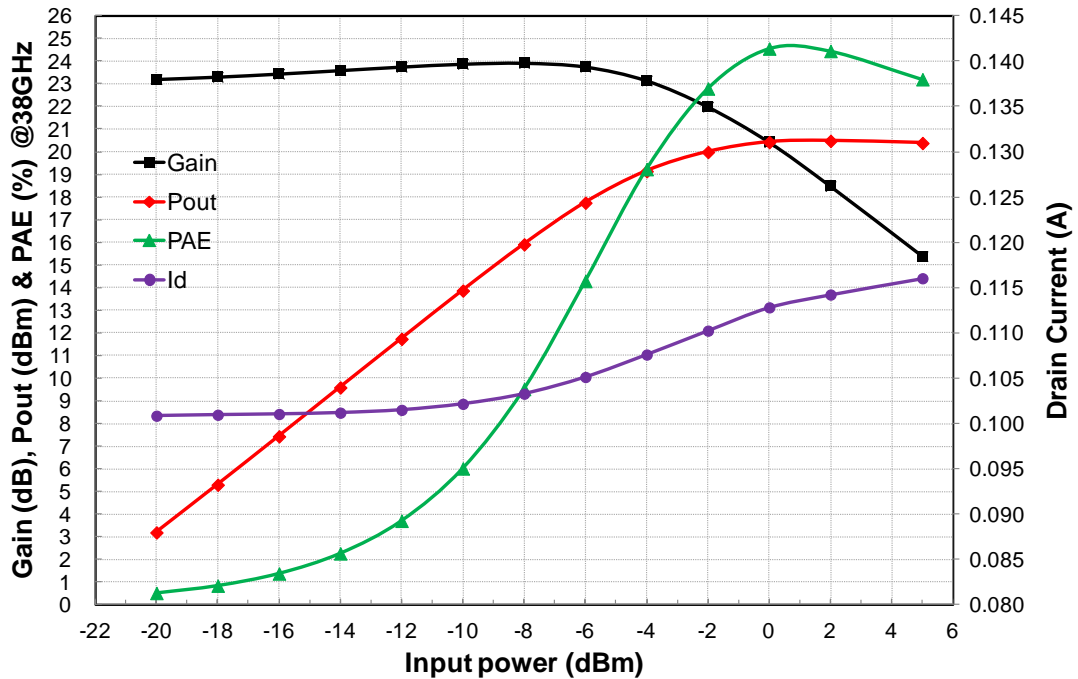
Linear Gain & Gain, Pout & PAE versus Frequency @Pin=2dBm



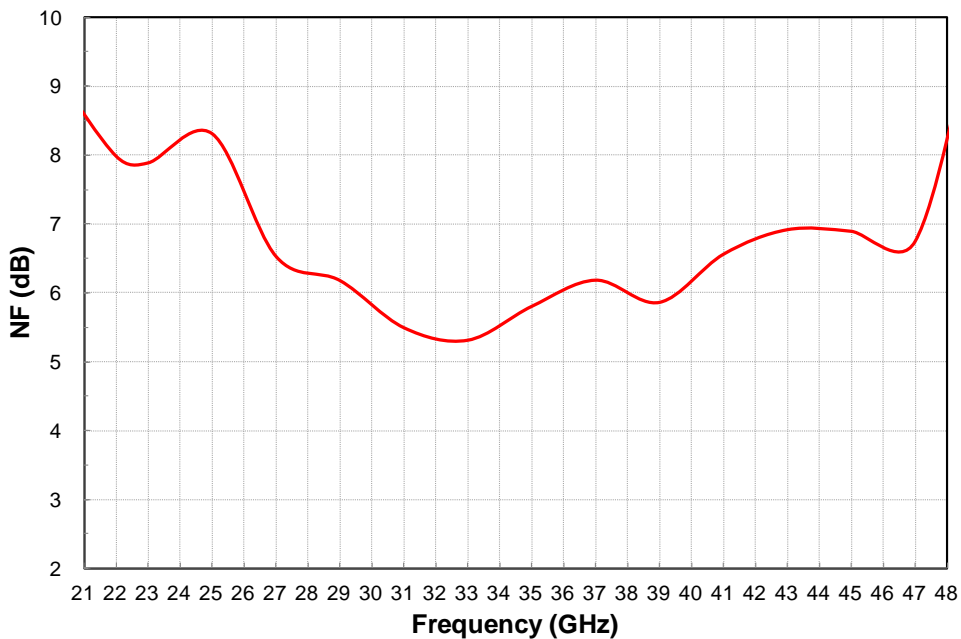
Typical On Board Measurements (CW)

Tamb = +25°C, Vd = +4V, Vg1=-4V, other Vg fixed for Idq = 100mA@25°C
 Measurement performed on test board in the bonding wire access plans on the PCB.

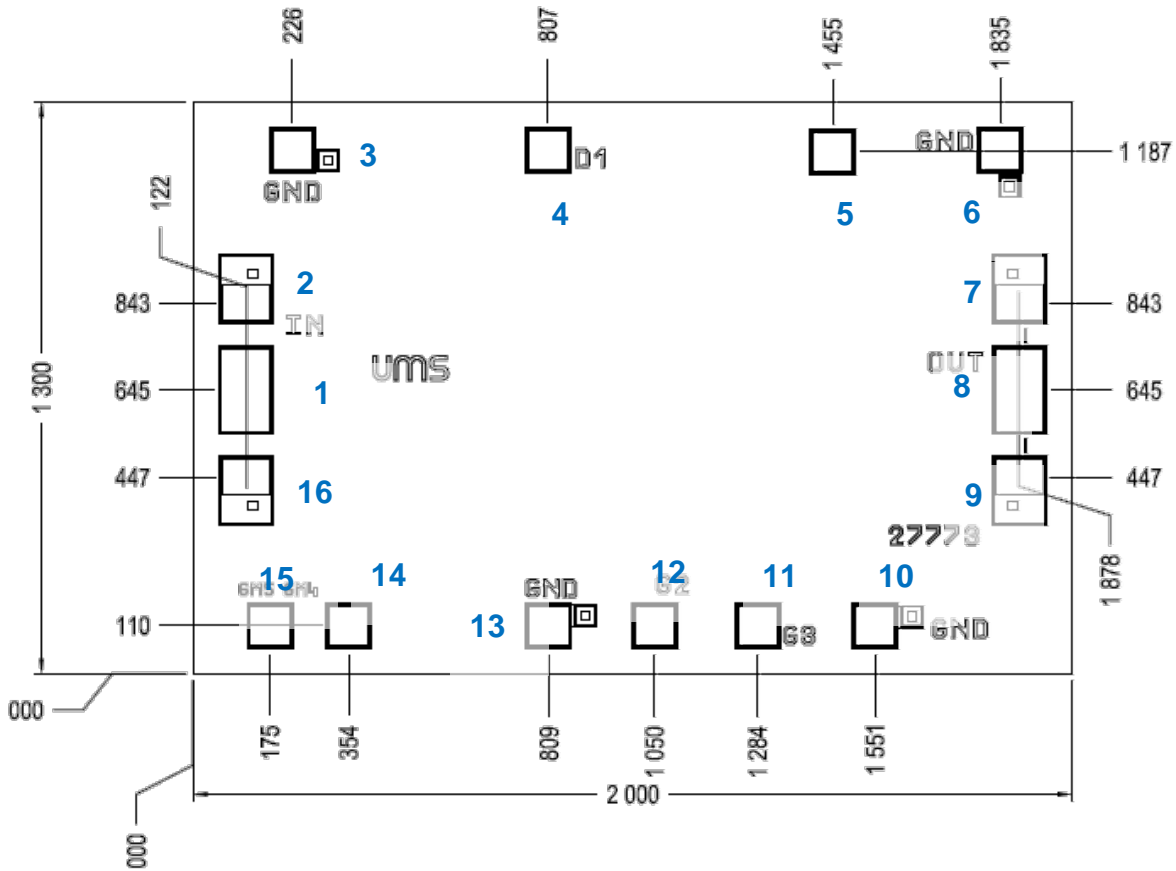
Gain, Pout, PAE & Id versus Pin @Freq=38GHz



Noise Figure @25°C versus Frequency



Mechanical data

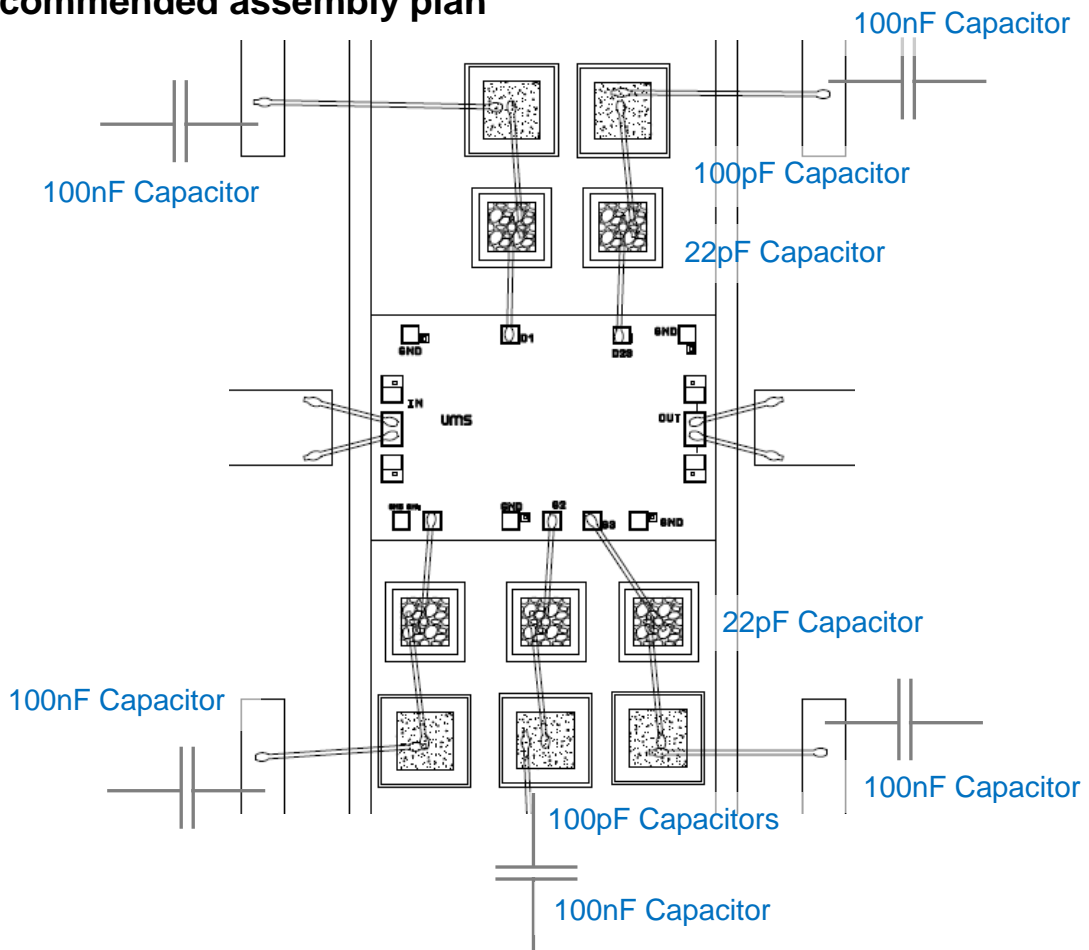


Tolerance chip size : +/-50µm
 Chip thickness: 70µm.
 All dimensions are in micrometers

| PAD Number | Name | Description | Pad size (BCB Opening) |
|--------------|--------------------|--|------------------------|
| 1 | IN | Input RF port | 186µm x 110µm |
| 2, 7, 9, 16 | GND | Ground cross to RF Pad | 82µm x 108µm |
| 3, 6, 10, 13 | GND | Ground | 90µm x 90µm |
| 4 | D1 | DC Drain voltage 1 st stage | 90µm x 90µm |
| 5 | D23 | DC Drain voltage 2 nd & 3 rd stage | 90µm x 90µm |
| 8 | OUT | Output RF port | 186µm x 110µm |
| 11 | G3 | DC Gate voltage 3 rd stage | 90µm x 90µm |
| 12 | G2 | DC Gate voltage 2 nd stage | 90µm x 90µm |
| 14 | GM4 ⁽¹⁾ | DC Gate voltage 1 st stage : If -4V | 90µm x 90µm |
| 15 | GM5 ⁽¹⁾ | DC Gate voltage 1 st stage : If -5V | 90µm x 90µm |

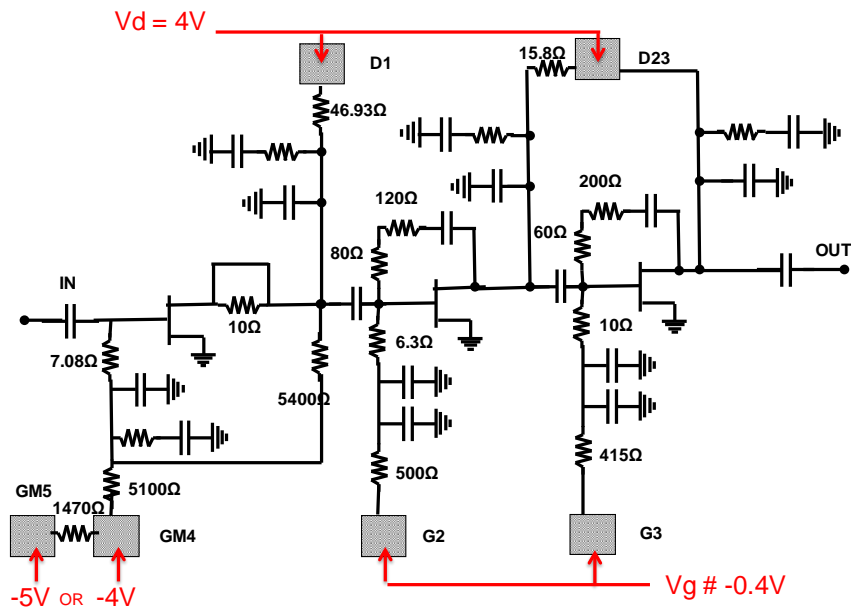
⁽¹⁾: Only 1 pad between GM4 and GM5 has to be connected, depend on external voltage using (-4V or -5V). There is only a resistor between GM4 and GM5 Pads.

Recommended assembly plan



Note: Supply feed should be bypassed. 25µm diameter gold wire is to be preferred.

DC Schematic



Recommended ESD management

Refer to the application note AN0020 available at <https://www.ums-rf.com> for ESD sensitivity and handling recommendations for the UMS products.

Recommended environmental management

UMS products are compliant with the regulation in particular with the directives RoHS N°2011/65 and REACH N°1907/2006. More environmental data are available in the application note AN0019 also available at <https://www.ums-rf.com>.

Ordering Information

Chip form:

CHA3409-98F/00

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